

650V SuperGaN® GaN FET in TO-220 (source tab)

Description

The TP65H150G4PS 650V, 150m Ω Gallium Nitride (GaN) FET is a normally-off device. It combines state-of-the-art high voltage GaN HEMT and low voltage silicon MOSFET technologies—offering superior reliability and performance.

The Gen IV SuperGaN® platform uses advanced epi and patented design technologies to simplify manufacturability while improving efficiency over silicon via lower gate charge, output capacitance, crossover loss, and reverse recovery charge.

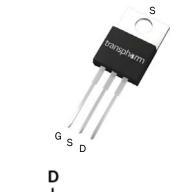
Related Literature

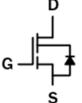
- ANOOO3: Printed Circuit Board Layout and Probing
- ANOOO7: Recommendations for Vapor Phase Reflow
- ANOOO9: Recommended External Circuitry for GaN FETs
- ANOO12: PQFN Tape and Reel Information

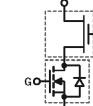
Product Series and Ordering Information

Part Number	Package	Package Configuration
TP65H150G4PS	3 lead T0-220	Source

TP65H0150G4PS T0-220 (top view)







Cascode Schematic Symbol

Cascode Device Structure

Features

- Gen IV technology
- JEDEC-qualified GaN technology
- Dynamic R_{DS(on)eff} production tested
- · Robust design, defined by
 - Wide gate safety margin
 - Transient over-voltage capability
- Very low QRR
- Reduced crossover loss
- RoHS compliant and Halogen-free packaging

Benefits

- Achieves increased efficiency in both hard- and softswitched circuits
 - Increased power density
 - Reduced system size and weight
 - Overall lower system cost
- · Easy to drive with commonly-used gate drivers
- GSD pin layout improves high speed design

Applications

- Consumer
- Power adapters
- Low power SMPS
- Lighting







Key Specifications			
V _{DS} (V) min	650		
V _{DSS(TR)} (V) max	800		
$R_{DS(on)}(m\Omega)$ max*	180		
Q _{RR} (nC) typ	40		
Q _G (nC) typ	8		

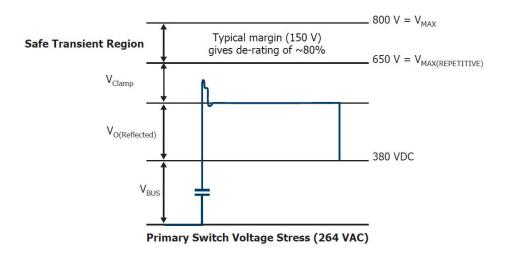
^{*} Dynamic R_{DS(on)}; see Figures 18 and 19

Absolute Maximum Ratings (T_c=25 °C unless otherwise stated.)

Symbol	Paramo	eter	Limit Value	Unit
V _{DSS}	Drain to source voltage (T _J = -	55°C to 150°C)	650	
V _{DSS(TR)}	Transient drain to source volta	age ^a	800	V
V _{GSS}	Gate to source voltage		±20	
P _D	Maximum power dissipation @	©Tc=25°C	52	W
1_	Continuous drain current @T _C =25°C b		13	A
I _D	Continuous drain current @T _C =100°C b		8.4	А
I _{DM}	Pulsed drain current (pulse w	Pulsed drain current (pulse width: 10µs)		A
Tc	Operating temperature	Case	-55 to +150	°C
Tı	Operating temperature	Junction	-55 to +150	°C
Ts	Storage temperature		-55 to +150	°C
T _{SOLD}	Reflow soldering temperature °		260	°C

Notes:

- a. In off-state, spike duty cycle D<0.01, spike duration $<30\mu s$. Nonrepetitive.
- b. For increased stability at high current operation, see Circuit Implementation on page 3
- c. Reflow MSL3



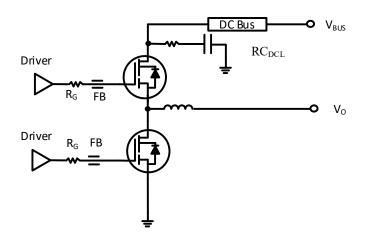
Thermal Resistance

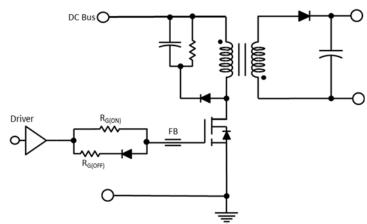
Symbol	Parameter	Typical	Unit
R _{ØJC}	Junction-to-case	2.4	°C/W
R _{OJA}	Junction-to-ambient ^d	50	°C/W

Notes:

d. Device on one layer epoxy PCB for drain connection (vertical and without air stream cooling, with 6cm² copper area and 70µm thickness)

Circuit Implementation





Simplified Half-bridge Schematic

Simplified Single Ended Schematic

Recommended gate drive: (0V, 10V) with $R_{\text{G(tot)}}\text{= }70~\Omega^{\text{a}}$

Recommended gate drive: (0V, 12V) with $R_{\text{G(0N)}}$ = 100 to 300 Ω $R_{G(OFF)}$ = 0 to 15 Ω

Gate Ferrite Bead (FB)	Required DC Link RC Snubber (RC _{DCL}) b
240Ω @ 100MHz	$4.7 \text{nF} + 2.5 \Omega$

Notes:

- a. For bridge topologies only. R_G could be much smaller in single ended topologies. b. RC_{DCL} should be placed as close as possible to the drain pin.

Electrical Parameters (T_J=25 °C unless otherwise stated)

Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions	
Forward Device Characteristics							
V _{DSS(BL)}	Maximum drain-source voltage	650	_	_	V	V _{GS} =0V	
$V_{GS(th)}$	Gate threshold voltage	3.3	4	4.8	V		
$\Delta V_{\text{GS(th)}}\!/T_{\text{J}}$	Gate threshold voltage temperature coefficient	_	-5.8	_	mV/°C	$V_{DS}=V_{GS}$, $I_{D}=0.5$ mA	
R _{DS(on)eff}	Drain-source on-resistance a	_	150	180	mΩ	V _{GS} =10V, I _D =8.5A, T _J =25°C	
NDS(on)eπ	Brain source of resistance	_	307	_	11122	V _{GS} =10V, I _D =8.5A, T _J =150°C	
I _{DSS}	Drain-to-source leakage current	_	2.5	25	- μA	V _{DS} =650V, V _{GS} =0V, T _J =25°C	
1000	Drain to course loanage carrent	_	10	_	μ, τ	V _{DS} =650V, V _{GS} =0V, T _J =150°C	
	Gate-to-source forward leakage current	_	_	100	A	V _{GS} =20V	
I _{GSS}	Gate-to-source reverse leakage current	_	_	-100	- nA	V _{GS} =-20V	
Ciss	Input capacitance	_	598	_		V _{GS} =0V, V _{DS} =400V, <i>f</i> =1MHz	
Coss	Output capacitance	_	30	_	pF		
C _{RSS}	Reverse transfer capacitance	_	1	_	-		
C _{O(er)}	Output capacitance, energy related b	_	43	_	, r.F	V _{GS} =0V, V _{DS} =0V to 400V	
$C_{O(tr)}$	Output capacitance, time related °	_	85	_	- pF		
Q _G	Total gate charge	_	8	_		V _{DS} =400V, V _{GS} =0V to 10V, I _D =10A	
Q _{GS}	Gate-source charge	_	3.3	_	nC		
Q_{GD}	Gate-drain charge	_	2	_			
Qoss	Output charge	_	34	_	nC	V _{GS} =0V, V _{DS} =0V to 400V	
t _{D(on)}	Turn-on delay	_	37.8	_		$\begin{array}{c} \text{V}_{\text{DS}}\text{=}400\text{V}, \text{V}_{\text{GS}}\text{=}0\text{V to }12\text{V}, \\ \text{I}_{\text{D}}\text{=}10\text{A}, \text{R}_{\text{G}}\text{=}70\Omega, \text{Z}_{\text{FB}}\text{=}240\Omega \text{ at } \\ 100\text{MHz} (\text{See Figure }14) \end{array}$	
t _R	Rise time	_	5.2	_	ne		
t _{D(off)}	Turn-off delay	_	48	_	ns		
t _F	Fall time	_	8	_			

- Dynamic R_{DS(on)} value; see Figures 18 and 19 for conditions Equivalent capacitance to give same stored energy from 0V to 400V
- Equivalent capacitance to give same charging time from OV to 400V

Electrical Parameters (T_J=25 °C unless otherwise stated)

Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions	
Reverse Device Characteristics							
Is	Reverse current	_	_	8.3	А	V _{GS} =0V, T _C =100°C, ≤20% duty cycle	
V Dovorce veltore 3	Povorco voltado a	_	2.4	_	V	V _{GS} =0V, I _S =10A	
V_{SD}	Reverse voltage ^a	_	1.6	_		V _{GS} =0V, I _S =5A	
t _{RR}	Reverse recovery time	_	31	_	ns	I _S =10A, V _{DD} =400V,	
Q _{RR}	Reverse recovery charge	_	40	_	nC	di/dt=1000A/ms	

Notes:

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a. Includes dynamic $R_{DS(on)}$ effect

Typical Characteristics (T_C=25 °C unless otherwise stated)

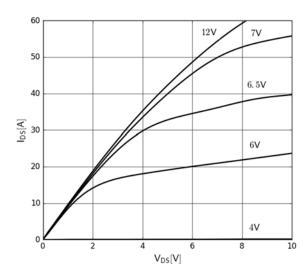
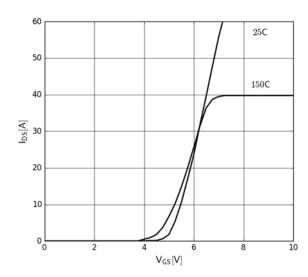


Figure 1. Typical Output Characteristics T_J=25 °C

Parameter: V_{GS}

Figure 2. Typical Output Characteristics T_J=150 °C

Parameter: V_{GS}



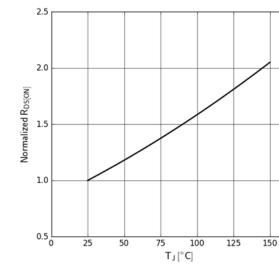


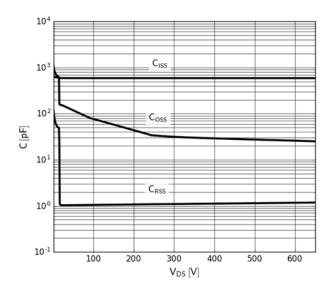
Figure 3. Typical Transfer Characteristics

Figure 4. Normalized On-resistance $I_D{=}16A,\,V_{GS}{=}10V$

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V_{DS}=10V, parameter: T_J

Typical Characteristics (T_C=25 °C unless otherwise stated)



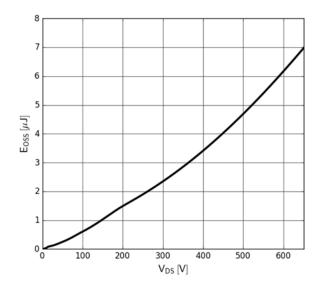
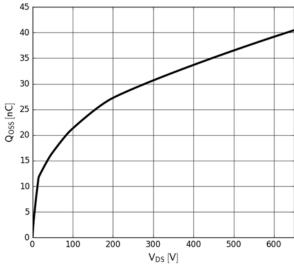


Figure 5. Typical Capacitance $V_{GS}=0V, f=1MHz$

Figure 6. Typical Coss Stored Energy





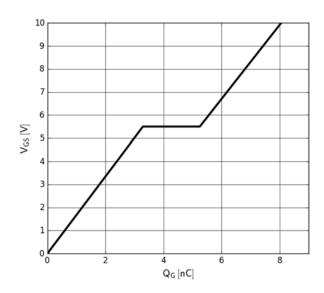


Figure 8. Typical Gate Charge IDS=10A, VDS=400V

Typical Characteristics (T_C=25 °C unless otherwise stated)

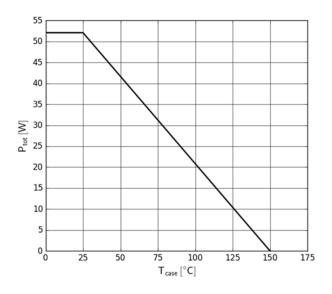


Figure 9. Power Dissipation

Figure 10. Current Derating Pulse width $\leq 10 \mu s$, $V_{GS} \geq 10 V$

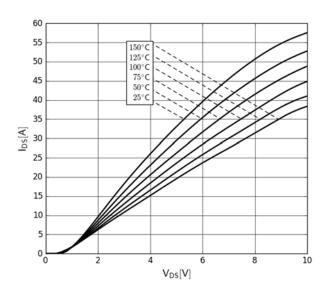


Figure 11. Forward Characteristics of Rev. Diode $I_S=f(V_{SD})$, parameter: T_J

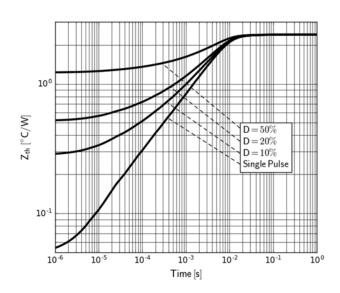


Figure 12. Transient Thermal Resistance

Typical Characteristics (T_C =25 °C unless otherwise stated)

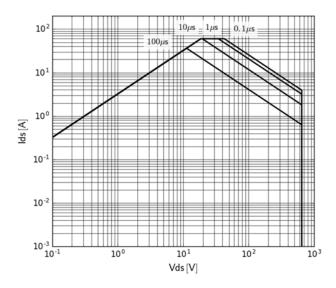


Figure 13. Safe Operating Area T_C=25°C

Test Circuits and Waveforms

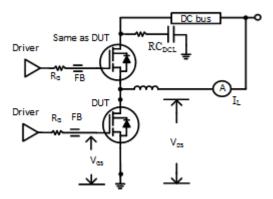


Figure 14. Switching Time Test Circuit (see circuit implementation on page 3 for methods to ensure clean switching)

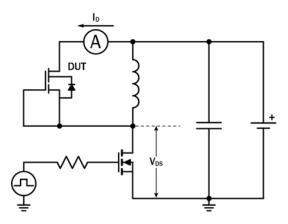


Figure 16. Diode Characteristics Test Circuit

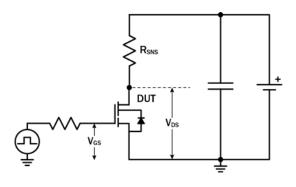


Figure 18. Dynamic R_{DS(on)eff} Test Circuit

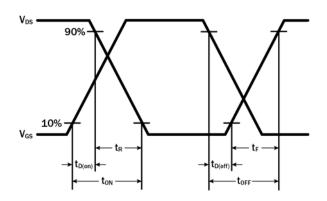


Figure 15. Switching Time Waveform

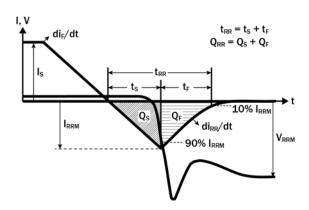


Figure 17. Diode Recovery Waveform

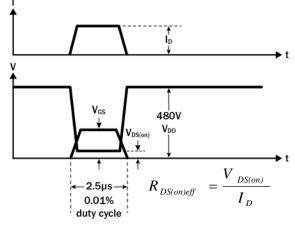


Figure 19. Dynamic R_{DS(on)eff} Waveform

Design Considerations

The fast switching of GaN devices reduces current-voltage crossover losses and enables high frequency operation while simultaneously achieving high efficiency. However, taking full advantage of the fast switching characteristics of GaN switches requires adherence to specific PCB layout guidelines and probing techniques.

Before evaluating Transphorm GaN devices, see application note <u>Printed Circuit Board Layout and Probing for GaN Power Switches</u>. The table below provides some practical rules that should be followed during the evaluation.

When Evaluating Transphorm GaN Devices:

DO	DO NOT
Minimize circuit inductance by keeping traces short, both in the drive and power loop	Twist the pins of TO-220 or TO-247 to accommodate GDS board layout
Minimize lead length of TO-220 and TO-247 package when mounting to the PCB	Use long traces in drive circuit, long lead length of the devices
Use shortest sense loop for probing; attach the probe and its ground connection directly to the test points	Use differential mode probe or probe ground clip with long wire
See ANOOO3: Printed Circuit Board Layout and Probing	

GaN Design Resources

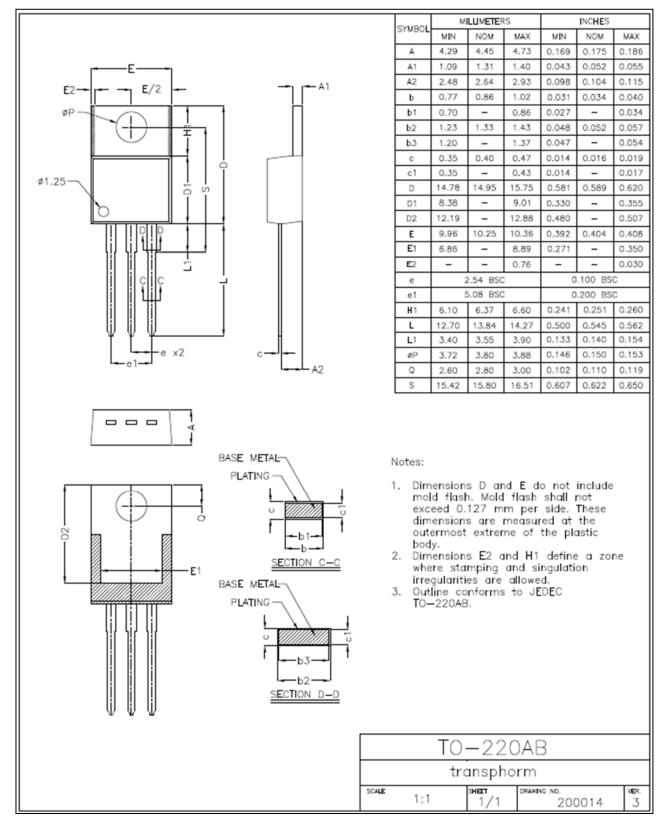
The complete technical library of GaN design tools can be found at transphormusa.com/design:

- Evaluation kits
- Application notes
- · Design guides
- Simulation models
- Technical papers and presentations

Mechanical

3 Lead TO-220 (PS) Package

Pin 1: Gate; Pin 2: Source; Pin 3: Drain, Tab: Source



Mechanical

Revision History

Version	Date	Change(s)	
0.1	6/2/2021	Preliminary Datasheet	
1.0	12/24/2021	Released	

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